

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BERTERO ET AL.	
		Examiner Kevin M Bernatz	Art Unit 1773	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-2002/0039668 ✓	04-2002	Inomata et al.	428/694.0TM
B	US-2003/0104247 ✓	06-2003	Girt, Erol	428/693
C	US-2003/0022023 ✓	01-2003	Carey et al.	428/694.0MM
D	US-2002/0132140 ✓	09-2002	Igarashi et al.	428/694.0TM
E	US-5,412,809	05-1995	Tam et al.	713/324
F	US-6,456,466	09-2002	Nakamoto et al.	360/319
G	US-2003/0035973 ✓	02-2003	Trindade et al.	428/494
H	US-2003/0108776 ✓	06-2003	Chang et al.	428/694.0TM
I	US-6,537,684	03-2003	Doerner et al.	428/611
J	US-2002/0045069 ✓	04-2002	SHINOHARA et al.	428/694.0TS
K	US-2001/0051287 ✓	12-2001	Kikitsu et al.	428/694.0ML
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
✓	U	Paper Titled "Preparation of Papers for 20th IEEE SOFE"
✓	V	Richter, H., Wu, W., and Malmhall, R., IEEE Trans. Mag., 34(4), 1998, 1540 - 1542.
✓	W	Richter, H., and Girt, E., IEEE Trans. Mag., 37(4), 2001, 1441 - 1444.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.